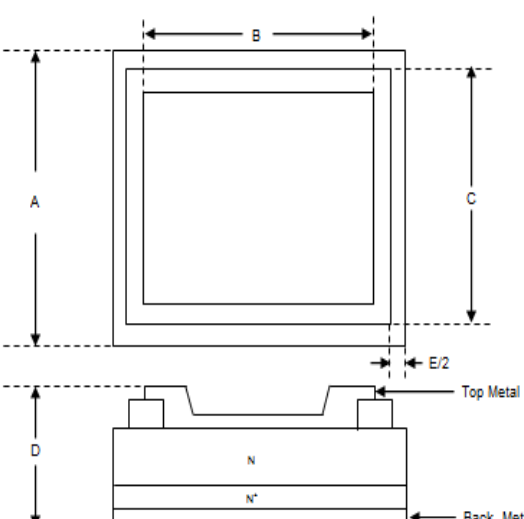


BMB2100BL

100V, 20A⁽¹⁾, TBR series Schottky

Mechanical Data

Chip Drawing	Item	Information	
	Die Size (A)	2845 μm	112 mil
	Top Metal Pad Size (B)	2668.4 μm	105 mil
	Passivation Seal (C)	2765.3 μm	108.9 mil
	Wafer Thickness (D)	254 \pm 15 μm	10 \pm 0.6 mil
	Scribe Line Width (E)	80 μm	3.15 mil
	Wafer Diameter	6 inch	
	Gross Die	1882	
	Top Side Metallization/ Layer Thickness	AL / 5 \pm 0.5 μm	
	Back Side Metallization/ Layer Thickness	Ag / 2 \pm 0.2 μm	
	Recommended Storage Environment	Store in original container, in dry nitrogen, (6 months at an ambient temperature of 23 $^{\circ}$ C \pm 3 $^{\circ}$ C)	

Electrical Characteristics in C/P test ($T_J = 25^{\circ}\text{C}$)

Parameter	Description	Min.	Typ.	Max.	Unit	Test Condition
V_{BR}	Reverse Breakdown Voltage	100	—	—	V	$I_R = 300\mu\text{A}$
V_F	Instantaneous Forward Voltage	—	0.44	0.465	V	$I_F = 3\text{A}^{(2)}$
		—	0.57	0.63	V	$I_F = 10\text{A}^{(2)}$
I_R	Reverse Leakage Current	—	14.5	30	μA	$V_R = 100\text{V}$
T_J, T_{STG}	Operating and Storage Temperature	-40 $^{\circ}$ C to 150 $^{\circ}$ C Max				